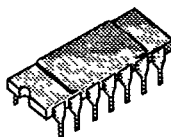


VQ2006 SERIESP-Channel Enhancement-Mode MOS Transistor
Arrays**Siliconix**
incorporated

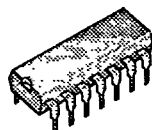
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PRODUCT SUMMARY

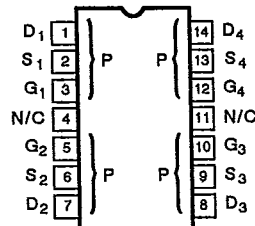
PART NUMBER	$V_{(BR)DSS}$ (V)	$r_{DS(ON)}$ (Ω)	I_D (A)	PACKAGE
VQ2006J	-90	5	-0.41	Plastic
VQ2006P	-90	5	-0.41	Side Braze

14-PIN DIP
SIDE BRAZE

14-PIN PLASTIC

**TOP VIEW**

Dual-In-Line Package



Performance Curves: VPDV10 (See Section 7)

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	VQ2006J	VQ2006P	UNITS
Drain-Source Voltage		V _{DS}	-90	-90	V
Gate-Source Voltage		V _{GS}	±30	±20	
Continuous Drain Current	T _A = 25°C	I _D	-0.41	-0.41	A
	T _A = 100°C		-0.23	-0.23	
Pulsed Drain Current ¹		I _{DM}	±3	±3	
Power Dissipation – Single	T _A = 25°C	P _D	1.3	1.3	W
	T _A = 100°C		0.52	0.52	
Power Dissipation – Quad	T _A = 25°C		2	2	
	T _A = 100°C		0.8	0.8	
Operating Junction and Storage Temperature		T _J , T _{stg}	-55 to 150		°C
Lead Temperature (1/16" from case for 10 seconds)		T _L	300		

THERMAL RESISTANCE

THERMAL RESISTANCE	SYMBOL	VQ2006J	VQ2006P	UNITS
Junction-to-Ambient - Single	R_{thJA}	96.2	96.2	$^\circ\text{C/W}$
Junction-to-Ambient - Quad		62.5	62.5	

¹Pulse width limited by maximum junction temperature



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VQ2006 SERIES

ELECTRICAL CHARACTERISTICS ¹				LIMITS		
PARAMETER	SYMBOL	TEST CONDITIONS	TYP ²	VQ2006 ⁴		UNIT
				MIN	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = -10 μA	-110	-90		V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -1 mA	-3.4	-2	-4.5	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V V _{GS} = ±30 V T _J = 125°C	± 1 ± 5		± 100 ± 500	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -90 V V _{GS} = 0 V T _J = 125°C	-0.0005 -0.1		-10 -500	μA
On-State Drain Current ³	I _{D(ON)}	V _{DS} = -10 V, V _{GS} = -10 V	-2	-1		A
Drain-Source On-Resistance ³	r _{DS(ON)}	V _{GS} = -10 V I _D = -1 A T _J = 125°C	2.5 4.3		5 8	Ω
Forward Transconductance ³	g _{FS}	V _{DS} = -10 V, I _D = -0.5 A	325	200		mS
Common Source Output Conductance ³	g _{OS}	V _{DS} = -7.5 V, I _D = -0.1 A	450			μS
DYNAMIC						
Input Capacitance	C _{iss}	V _{DS} = -25 V V _{GS} = 0 V f = 1 MHz	75		150	pF
Output Capacitance	C _{oss}		40		60	
Reverse Transfer Capacitance	C _{rss}		18		25	
SWITCHING						
Turn-On Time	t _{d(ON)}	V _{DD} = -25 V, R _L = 47 Ω I _D = -0.5 A, V _{GEN} = -10 V R _G = 25 Ω (Switching time is essentially independent of operating temperature)	11		15	ns
	t _r		30		40	
Turn-Off Time	t _{d(OFF)}		20		30	
	t _f		20		30	

- NOTES: 1. $T_A = 25^\circ\text{C}$ unless otherwise noted.
 2. For design aid only, not subject to production testing.
 3. Pulse test; $PW = 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
 4. Data sheet limits have been revised.